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Zou et al.

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(54) **CONFIGURABLE BUILT-IN SELF-REPAIR CHAIN FOR FAST REPAIR DATA LOADING**

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CPC **G11C 29/10** (2013.01); **G11C 29/12015** (2013.01); **G11C 29/32** (2013.01); **G11C 29/4401** (2013.01); **G11C 29/789** (2013.01)
(58) **Field of Classification Search**
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See application file for complete search history.

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(57) **ABSTRACT**
A scan network configured to transport repair information between memories and a controller for a non-volatile storage device comprises: repair registers coupled in parallel to repair information generation circuitry for one of the memories and segment selection devices that divide the repair registers into repair register segments. Each of the segment selection devices comprises: a storage element configured to store a segment selection bit and segment selection bit generation circuitry configured to generate the segment selection bit based on the repair information. Each of the segment selection devices is configurable to include or not include the corresponding repair register segment in a scan path of the scan network in a shift operation based on the segment selection bit.

24 Claims, 14 Drawing Sheets

